

IGBT

TRENCHSTOP™ IGBT3 Chip SIGC15T65E

Data Sheet

Industrial Power Control



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TRENCHSTOP[™] IGBT3 Chip

Features:

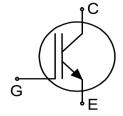
- 650V trench & field stop technology
- Low V_{CEsat}
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling

Recommended for:

Power modules

Applications:

Drives



Chip Type	V _{CE}	I Cn	Die Size	Package
SIGC15T65E	650V	30A	3.92mm x 3.88mm	Sawn on foil

Mechanical Parameters

Die size		3.92 x 3.88			
Emitter pad size		See chip drawing			
Gate pad size		0.608 x 1.083			
Area total		15.21			
Silicon thickness		70	μm		
Wafer size		200	mm		
Maximum possible ch	ips per wafer	1806			
Passivation frontside		Photoimide			
Pad metal		3200nm AlSiCu			
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		Al, ≤500μm			
Reject ink dot size		Ø 0.65mm; max. 1.2mm			
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C			
(<6 months)	for open MBB bags	Acc. IEC 62258-3; Section 9.4 Storage Environment.			



Maximum Ratings

In general, from reliability and lifetime point of view, the lower the operation junction temperature and/or the applied voltage, the greater the expected lifetime of any semiconductor device.

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T_{vj} =25°C	V _{CE}	650	V
DC collector current, limited by $T_{\rm vj\;max}^{\;\;\;1}$	I _C	-	Α
Pulsed collector current, t_p limited by $T_{vj \max}^2$	I _{C,puls}	90	Α
Gate-emitter voltage	V_{GE}	±20	V
Virtual junction temperature	$T_{\rm vj}$	-40 +175	°C
Short circuit data $^{1/2/3}$ $V_{GE}=15V$, $V_{CC}=360V$, $T_{Vj}=150$ °C	$t_{ m sc}$	6	μs

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol	Conditions	Value			Unit
- arameter			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	V_{GE} =0V, I_{C} =2mA	650	-	-	
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =30A	1.03	1.45	1.87	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =430 μ A, $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4	
Zero gate voltage collector current	I _{CES}	$V_{CE} = 650 \text{V}, \ V_{GE} = 0 \text{V}$	-	-	1.6	μA
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$	-	-	300	nA
Integrated gate resistor	r _G			none		Ω

Electrical Characteristics ²

Parameter	Symbol Conditions		Value			Unit
raiailletei	Syllibol	Conditions	min.	typ.	max.	Onit
Collector-emitter saturation voltage	V_{CEsat}	V_{GE} =15V, I_{C} =30A, T_{vj} =175°C	-	1.9	-	V
Input capacitance	C _{ies}	V _{CE} =25V,	-	1630	-	nE
Reverse transfer capacitance	C _{res}	V_{GE} =0V, f =1MHz T_{Vj} =25°C	-	50	-	pF

L7551M, L7551Y 4 Rev. 2.2, 25.01.2017

¹ Depending on thermal properties of assembly.

² Not subject to production test - verified by design/characterization.

³ Allowed number of short circuits: <1000; time between short circuits: >1s.



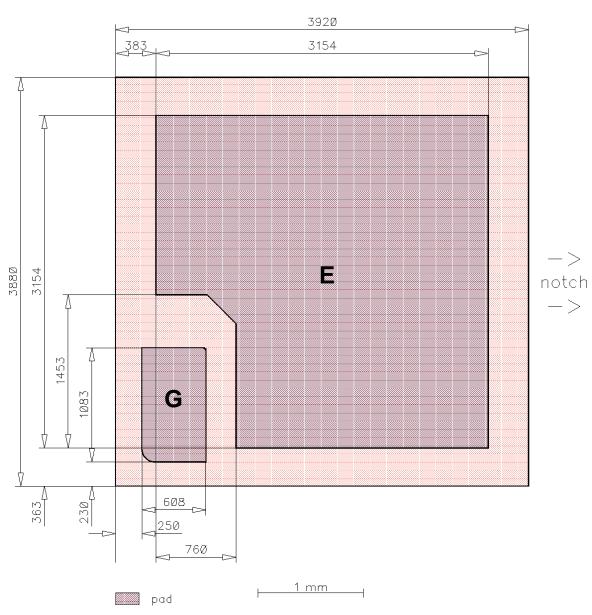
Further Electrical Characteristics

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing





E = Emitter

G = Gate



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	02.02.2015
2.1	Additional Basic Type, editorial changes	04.11.2016
2.2	Editorial changes	25.01.2017

Relevant Application Notes



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